


<b>Search Notes</b>  	<b>Application/Control No.</b>  10574052	<b>Applicant(s)/Patent Under Reexamination</b>  TAKAHASHI ET AL.
	<b>Examiner</b>  Lucas Stelling	<b>Art Unit</b>  1797

SEARCHED			
Class	Subclass	Date	Examiner
210	748+, 749, 760, 761, 765, 766, 167.01, 194, 195.1, 198.1, 205,	2/18/2010	/LS/
261	76, 94	2/18/2010	/LS/
366	336, 340, 174.1, 175.2,	2/18/2010	/LS/
138	40, 41	2/18/2010	/LS/

SEARCH NOTES		
Search Notes	Date	Examiner
inventor name search in eDAN	2/18/2010	/LS/
keywords used -- microbubble, nanobubble, cavitation, micron, nozzle,	2/18/2010	/LS/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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